

REVISIONS																							
LTR	DESCRIPTION	DATE (YR-MO-DA)	APPROVED																				
REV																							
SHEET																							
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SHEET	22	23																					
REV STATUS OF SHEETS	REV																						
	SHEET		1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
PMIC N/A	PREPARED BY <i>Charles Reusing</i>		DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444																				
STANDARDIZED MILITARY DRAWING	CHECKED BY <i>Charles Reusing</i>																						
	APPROVED BY <i>[Signature]</i>																						
	DRAWING APPROVAL DATE 9 OCTOBER 1990																						
THIS DRAWING IS AVAILABLE FOR USE BY ALL DEPARTMENTS AND AGENCIES OF THE DEPARTMENT OF DEFENSE	REVISION LEVEL		MICROCIRCUITS, MEMORY, DIGITAL, CMOS 256 X 9 PARALLEL FIFO, MONOLITHIC SILICON																				
AMSC N/A			SIZE A	CAGE CODE 67268		5962-89666																	
			SHEET 1																				

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U.S. GOVERNMENT PRINTING OFFICE: 1987 - 748-129/60911

DISTRIBUTION STATEMENT A. Approved for public release; distribution is unlimited.

5962-E1562

2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

SPECIFICATION

MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

STANDARD

MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

BULLETIN

MILITARY

MIL-BUL-103 - List of Standardized Military Drawings (SMD's).

(Copies of the specification, standard, and bulletin required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth tables. The truth tables shall be as specified on figure 2.

3.2.3 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and shall apply over the full case operating temperature range.

3.4 Electrical test requirements. The electrical test requirements shall be the subgroups specified in table II. The electrical tests for each subgroup are described in table I.

3.5 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in MIL-BUL-103 (see 6.6 herein).

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TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V ≤ V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Input leakage current	I _{LI}	0.0 V ≤ V _{IN} ≤ V _{CC}	1, 2, 3	A11	-10	10	μA
Output leakage current	I _{LO}	0.0 V ≤ V _{OUT} ≤ V _{CC} , R̄ ≥ V _{IH}	1, 2, 3	A11	-10	10	μA
Output low voltage	V _{OL}	V _{CC} = 4.5 V, I _{OL} = 8.0 mA, V _{IL} = 0.8 V, V _{IH} = 2.2 V	1, 2, 3	A11		0.4	V
Output high voltage	V _{OH}	V _{CC} = 4.5 V, I _{OH} = -2.0 mA, V _{IL} = 0.8 V, V _{IH} = 2.2 V	1, 2, 3	A11	2.4		V
Operating supply current	I _{CC1}	f = f _S , outputs open, V _{CC} = 5.5 V	1, 2, 3	01,02, 03,04		100	mA
		f = 20 MHz, outputs open, V _{CC} = 5.5 V		05,06	140		
Standby power supply current	I _{CC2}	R = W = RS = FL/RT = V _{IH} , outputs open	1, 2, 3	01,02, 03,04		15	mA
				05,06	20		
Power down current	I _{CC3}	All inputs = V _{CC} - 0.2 V, outputs open	1, 2, 3	A11		900	μA
Input capacitance	C _{IN}	V _I = 0 V, f = 1.0 MHz, T _A = +25°C, see 4.3.1c	4	A11		8	pF
Output capacitance	C _{OUT}	V _O = 0 V, f = 1.0 MHz, T _A = +25°C, see 4.3.1c	4	A11		8	pF
Shift frequency	f _S	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01		7.0	MHz
				02		10	
				03		12.5	
				04		15	
				05		20	
				06		25	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Read cycle time	t _{RC}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01	140		ns
				02	100		
				03	80		
				04	65		
				05	50		
				06	40		
Access time	t _A		9, 10, 11	01		120	
				02		80	
				03		65	
				04		50	
				05		40	
				06		30	
Read recovery time	t _{RR}		9, 10, 11	01,02	20		ns
				03,04	15		
				05,06	10		
Read pulse width	t _{RPW}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		

See footnotes at end of table.

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* U. S. GOVERNMENT PRINTING OFFICE: 1988-549-904

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Read pulse low to data bus at low Z <u>1/</u>	t _{RLZ}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01,02, 03,04	10		ns
				05,06	5.0		
Write pulse low to data bus at low Z <u>1/ 2/</u>	t _{WLZ}		9, 10, 11	01,02	20		ns
				03,04	15		
				05	10		
				06	5.0		
Data valid from read pulse high	t _{DV}		9, 10, 11	A11	5.0		ns
Read pulse high to data bus at high Z <u>1/</u>	t _{RHZ}		9, 10, 11	01		35	ns
				02,03, 04		30	
				05		25	
				06		20	
Write cycle time	t _{WC}		9, 10, 11	01	140		ns
				02	100		
				03	80		
				04	65		
				05	50		
				06	40		
Write pulse width	t _{WPW}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		

See footnotes at end of table.

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* U. S. GOVERNMENT PRINTING OFFICE 1968--549-904

TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Write recovery time	t _{WR}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01,02	20		ns
				03,04	15		
				05,06	10		
Data setup time	t _{DS}		9, 10, 11	01,02	40		ns
				03,04	30		
				05	20		
				06	18		
Data hold time	t _{DH}		9, 10, 11	01,02, 03	10		ns
				04	5.0		
				05,06	0.0		
Reset cycle time	t _{RSC}		9, 10, 11	01	140		ns
				02	100		
				03	80		
				04	65		
				05	50		
				06	40		
Reset pulse width	t _{RS}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		
Reset recovery time	t _{RSR}		9, 10, 11	01,02	20		ns
				03,04	15		
				05,06	10		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Reset setup time	t _{RSS}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		
Retransmit cycle time	t _{RTC}		9, 10, 11	01	140		ns
				02	100		
				03	80		
				04	65		
				05	50		
				06	40		
Retransmit pulse width	t _{RT}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		
Retransmit recovery time	t _{RTR}		9, 10, 11	01,02	20		ns
				03,04	15		
				05,06	10		

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Reset to empty flag low	t _{EFL}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01		140	ns
				02		100	
				03		80	
				04		65	
				05		50	
				06		40	
Read low to empty flag low	t _{REF}		9, 10, 11	01,02, 03		60	ns
				04		45	
				05,06		30	
Read high to full flag high	t _{RFF}		9, 10, 11	01,02, 03		60	ns
				04		45	
				05		35	
				06		30	
Write high to empty flag high	t _{WEF}		9, 10, 11	01,02, 03		60	ns
				04		45	
				05		35	
				06		30	
Write low to full flag low	t _{WFF}		9, 10, 11	01,02, 03		60	ns
				04		45	
				05		35	
				06		30	

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Reset to half-full and full flag high	t _{HFH} , t _{FFH}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01		140	ns
				02		100	
				03		80	
				04		65	
				05		50	
				06		40	
Read/Write to $\overline{X0}$ low	t _{X0L}		9, 10, 11	01		120	ns
				02		80	
				03		65	
				04		50	
				05		40	
				06		30	
Read/Write to $\overline{X0}$ high	t _{X0H}		9, 10, 11	01		120	ns
				02		80	
				03		65	
				04		50	
				05		40	
				06		30	
\overline{XI} pulse width	t _{XI}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		

See footnotes at end of table.

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TABLE 1. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit	
					Min	Max		
\overline{X} I recovery time	t _{XIR}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	A11	10		ns	
XI setup time	t _{XIS}			A11	15		ns	
Retransmit setup time	t _{RTS}			9, 10, 11	01	120		ns
					02	80		
					03	65		
					04	50		
		05	40					
		06	30					
Read pulse width after EF high	t _{RPE}	9, 10, 11	01	120		ns		
			02	80				
			03	65				
			04	50				
			05	40				
			06	30				
Write low to half-full flay low	t _{WHF}	9, 10, 11	01		140	ns		
			02		100			
			03		80			
			04		65			
			05		50			
			06		40			

See footnotes at end of table.

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TABLE I. Electrical performance characteristics - Continued.

Test	Symbol	Conditions -55°C < T _C < +125°C V _{SS} = 0 V, 4.5 V < V _{CC} < 5.5 V unless otherwise specified	Group A subgroups	Device types	Limits		Unit
					Min	Max	
Read high to half-full flag high	t _{RHF}	C _L = 30 pF, see figures 3 and 4	9, 10, 11	01		140	ns
				02		100	
				03		80	
				04		65	
				05		50	
				06		40	
Write pulse width after FF high	t _{WPF}		9, 10, 11	01	120		ns
				02	80		
				03	65		
				04	50		
				05	40		
				06	30		

1/ If not tested, shall be guaranteed to the limits specified in table I.

2/ Only applies to read data flow-through mode.

3.6 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in MIL-BUL-103 (see 6.6 herein). The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall affirm that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

3.7 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.8 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.9 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

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Device types	All	
Case outlines	X, Y, and Z	U
Terminal number	Terminal symbol	
1	W	NC
2	D8	W
3	D3	D8
4	D2	D3
5	D1	D2
6	D0	D1
7	XI	D0
8	FF	XI
9	Q0	FF
10	Q1	Q0
11	Q2	Q1
12	Q3	NC
13	Q8	Q2
14	GND	Q3
15	R	Q8
16	Q4	GND
17	Q5	NC
18	Q6	R
19	Q7	Q4
20	XO/HF	Q5
21	EF	Q6
22	RS	Q7
23	FL/RT	XO/HF
24	D7	EF
25	D6	RS
26	D5	FL/RT
27	D4	NC
28	VCC	D7
29	---	D6
30	---	D5
31	---	D4
32	---	VCC

FIGURE 1. Terminal connections.

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Reset and transmit
Single device configuration/width expansion mode

Mode	Inputs			Internal status		Outputs		
	RS	RT	XI	Read pointer	Write pointer	EF	FF	HF
Reset	0	X	0	Location zero	Location zero	0	1	1
Retransmit	1	0	0	Location zero	Unchanged	X	X	X
Read/Write	1	1	0	Increment (see note)	Increment (see note)	X	X	X

NOTE: Pointer will increment if flag is high.

Reset and first load
Depth expansion/compound expansion mode

Mode	Inputs			Internal status		Outputs	
	RS	FL	XI	Read pointer	Write pointer	EF	FF
Reset first device	0	0	See note 2	Location zero	Location zero	0	1
Reset all other devices	0	1	See note 2	Location zero	Location zero	0	1
Read/Write	1	X	See note 2	X	X	X	X

NOTES:

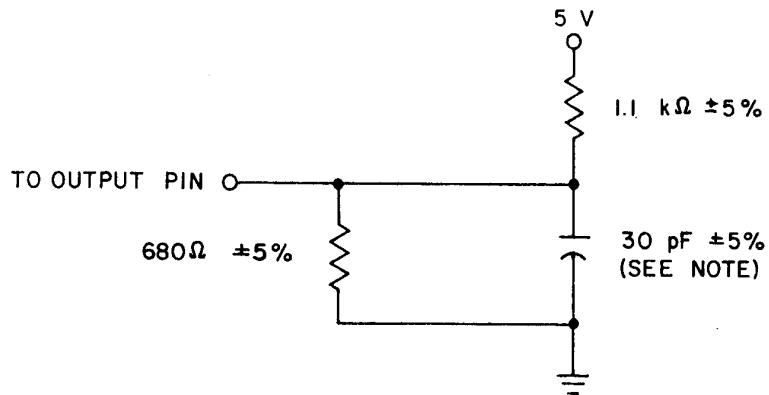
1. RS = Reset input, FL/RT = First load/retransmit, EF = Empty flag output, FF = Full flag output, XI = Expansion input, and HF = Half-full flag output
0 = Low level voltage
1 = High level voltage
X = Don't care
2. XI is connected to $\overline{X0}$ of previous device.

FIGURE 2. Truth tables.

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NOTE: C_L includes scope and jig capacitance.

AC test conditions

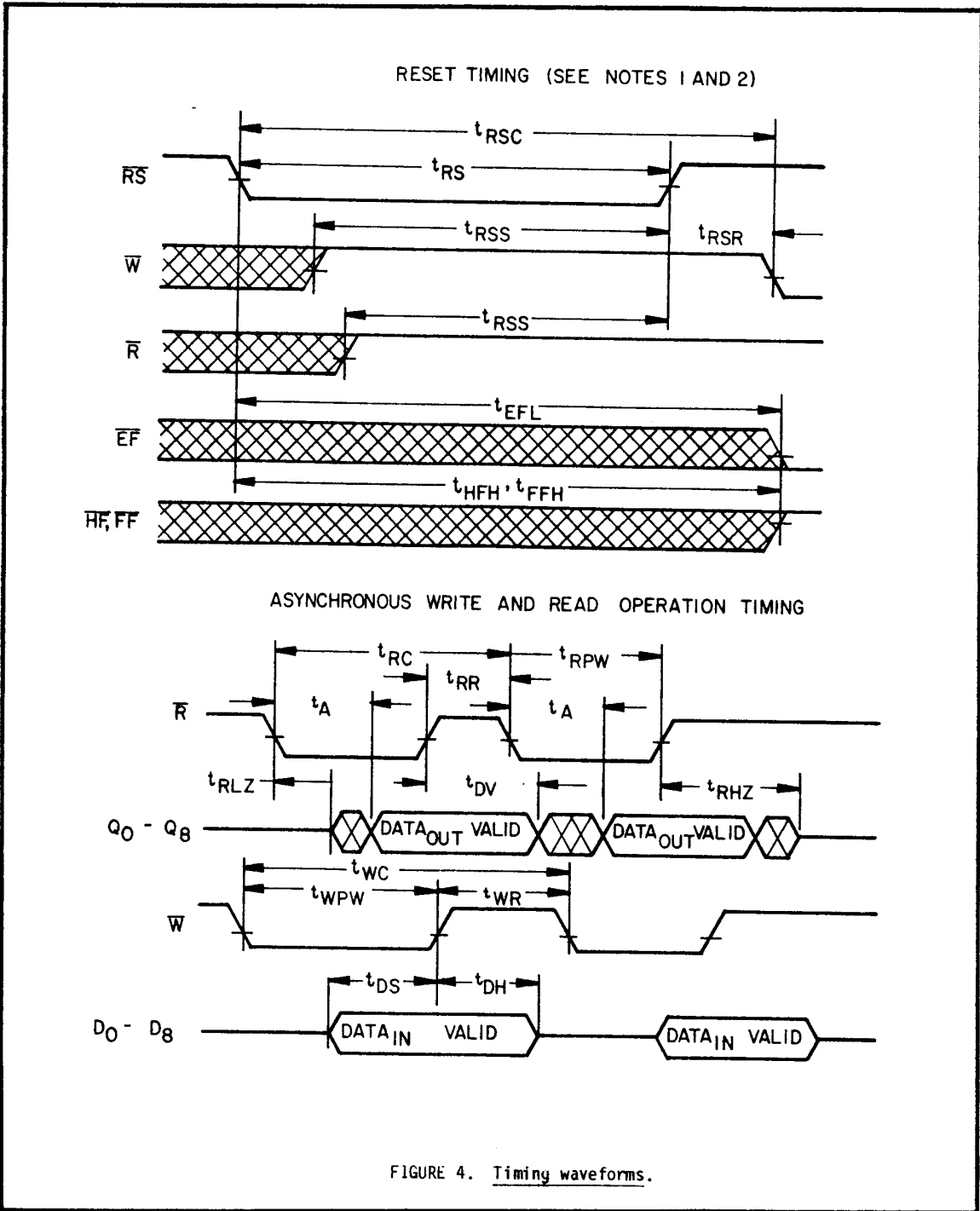
Input pulse levels	GND to 3.0 V
Input rise and fall times	5 ns
Input timing reference levels	1.5 V
Output reference levels	1.5 V

FIGURE 3. Output load circuit and ac test conditions.

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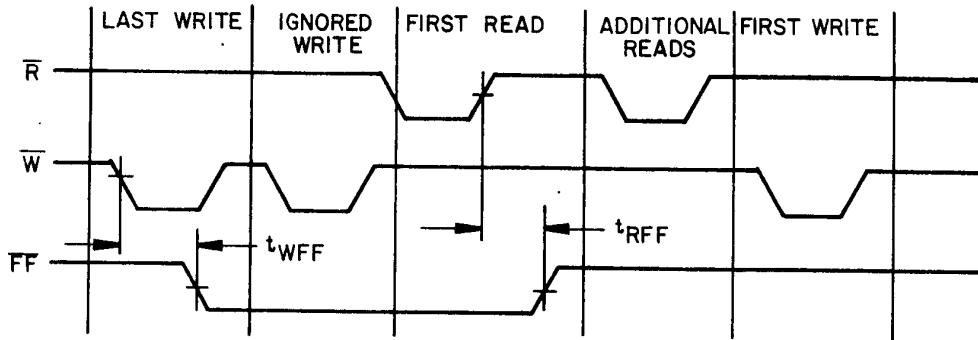


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FULL FLAG FROM LAST WRITE TO FIRST READ



EMPTY FLAG FROM LAST READ TO FIRST WRITE

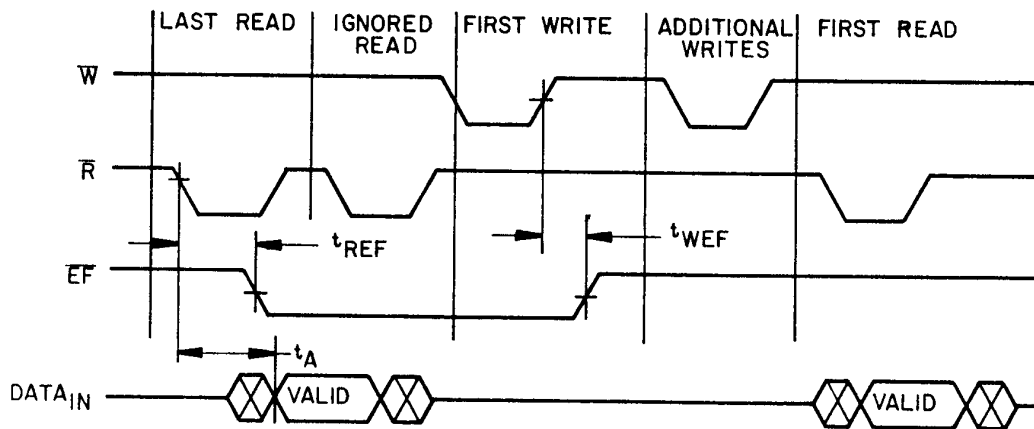


FIGURE 4. Timing waveforms - Continued.

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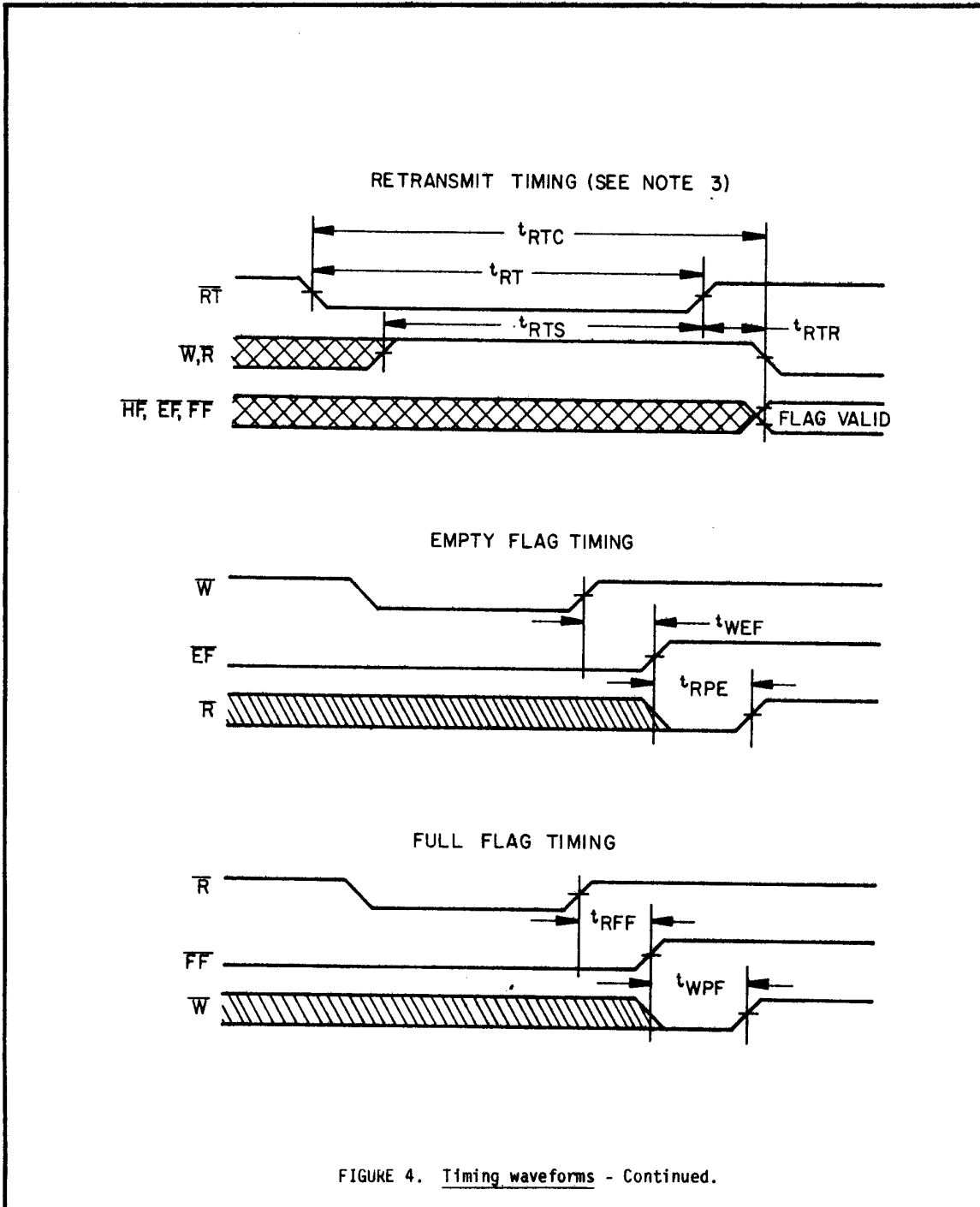


FIGURE 4. Timing waveforms - Continued.

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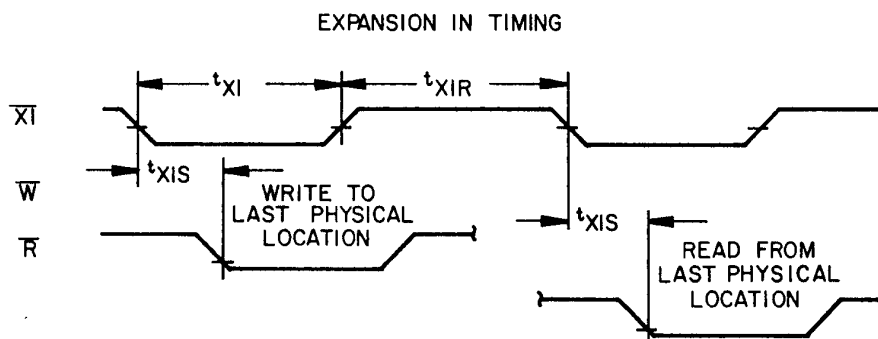
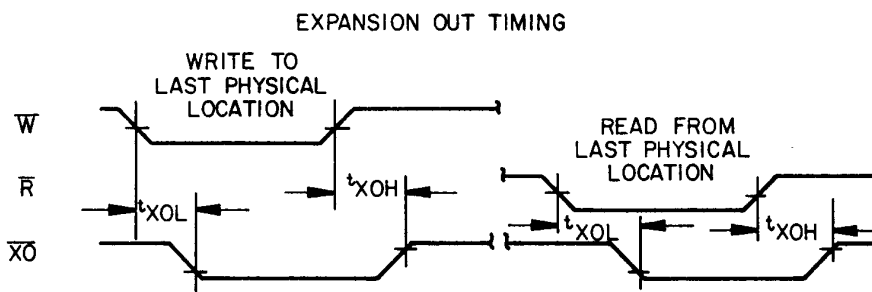
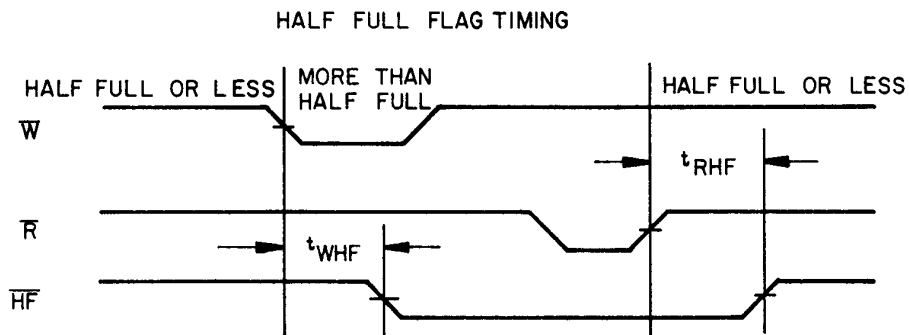
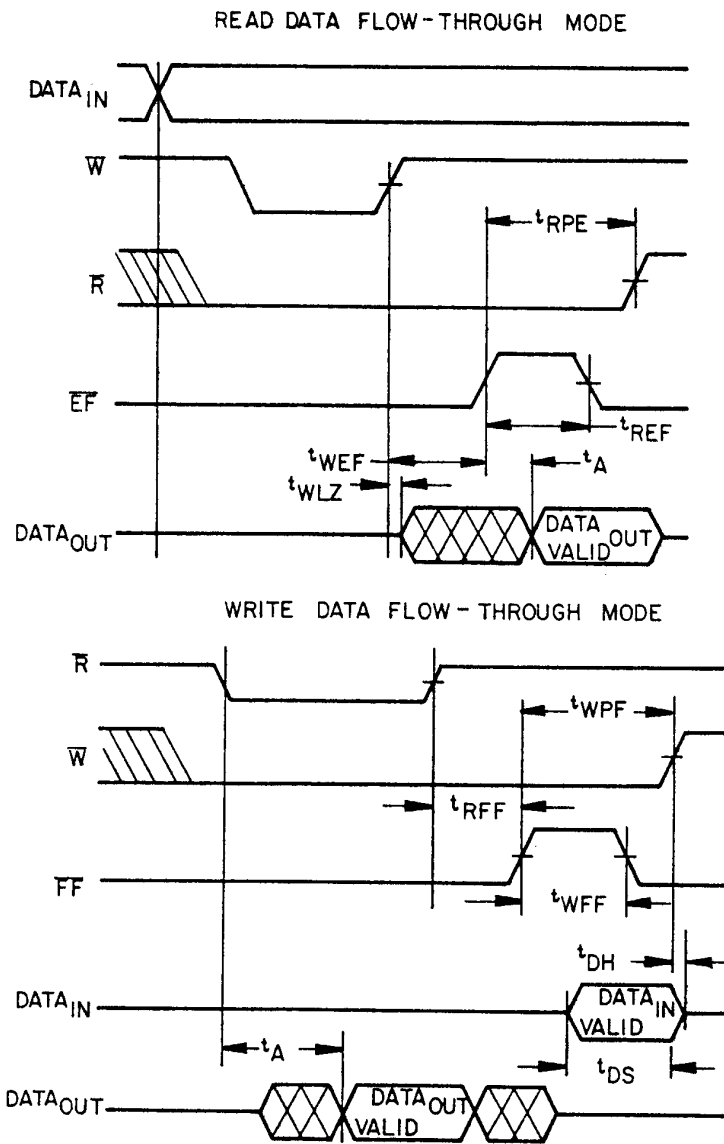


FIGURE 4. Timing waveforms - Continued.

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NOTES:

1. \overline{EF} , FF and HF may change status during reset, but flags will be at t_{RSC} .
2. \overline{W} and $\overline{R} = V_{IH}$ around the rising edge of RS.
3. During retransmit, EF, FF and HF may change status, but flags will be valid at t_{RTC} .

FIGURE 4. Timing waveforms - Continued.

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4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

- a. Burn-in test, method 1015 of MIL-STD-883.
 - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
- b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

4.3.1 Group A inspection.

- a. Tests shall be as specified in table II herein.
- b. Subgroups 5 and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.
- c. Subgroup 4 (C_{IN} and C_{OUT} measurements) shall be measured only for the initial test and after process or design changes which may affect capacitance. Sample size is 15 devices with no failures, and all input and output terminals tested.
- d. Subgroups 7 and 8 tests shall include verification of the truth table.

4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test conditions, method 1005 of MIL-STD-883:
 - (1) Test condition C or D using the circuit submitted with the certificate of compliance (see 3.6 herein).
 - (2) $T_A = +125^\circ\text{C}$, minimum.
 - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

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TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*,2,3,7*,8A, 8B,9,10,11
Group A test requirements (method 5005)	1,2,3,4**,7,8A, 8B,9,10,11
Groups C and D end-point electrical parameters (method 5005)	2,3,7,8A,8B

* PDA applies to subgroups 1 and 7.
** See 4.3.1c

5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Configuration control of SMD's. All proposed changes to existing SMD's will be coordinated with the users of record for the individual documents. This coordination will be accomplished in accordance with MIL-STD-481 using DD Form 1693, Engineering Change Proposal (Short Form).

6.4 Record of users. Military and industrial users shall inform Defense Electronics Supply Center when a system application requires configuration control and the applicable SMD. DESC will maintain a record of users and this list will be used for coordination and distribution of changes to the drawings. Users of drawings covering microelectronics devices (FSC 5962) should contact DESC-ECS, telephone (513) 296-6022.

6.5 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio, 45444, or telephone (513) 296-5375.

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6.6 Approved source of supply. An approved source of supply is listed in MIL-BUL-103. Additional sources will be added to MIL-BUL-103 as they become available. The vendor listed in MIL-BUL-103 has agreed to this drawing and a certificate of compliance (see 3.6 herein) has been submitted to and accepted by DESC-ECS. The approved source of supply listed below is for information purposes only and is current only to the date of the last action of this document.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>
5962-8966601XX	61772	IDT7200L120TCB
5962-8966601YX	61772	IDT7200L120DB
5962-8966601ZX	61772	IDT7200L120XEB
5962-8966601UX	61772	IDT7200L120LB
5962-8966602XX	61772	IDT7200L80TCB
5962-8966602YX	61772	IDT7200L80DB
5962-8966602ZX	61772	IDT7200L80XEB
5962-8966602UX	61772	IDT7200L80LB
5962-8966603XX	61772	IDT7200L65TCB
5962-8966603YX	61772	IDT7200L65DB
5962-8966603ZX	61772	IDT7200L65XEB
5962-8966603UX	61772	IDT7200L65LB
5962-8966604XX	61772	IDT7200L50TCB
5962-8966604YX	61772	IDT7200L50DB
5962-8966604ZX	61772	IDT7200L50XEB
5962-8966604UX	61772	IDT7200L50LB
5962-8966605XX	61772	IDT7200L40TCB
5962-8966605YX	61772	IDT7200L40DB
5962-8966605ZX	61772	IDT7200L40XEB
5962-8966605UX	61772	IDT7200L40LB
5962-8966606XX	61772	IDT7200L30TCB
5962-8966606YX	61772	IDT7200L30DB
5962-8966606ZX	61772	IDT7200L30XEB
5962-8966606UX	61772	IDT7200L30LB

1/ Caution. Do not use this number for item acquisition. Items acquired to this number may not satisfy the performance requirements of this drawing.

<u>Vendor CAGE number</u>	<u>Vendor name and address</u>
61772	Integrated Device Technology, Incorporated 1566 Moffett Boulevard Salinas, CA 93905 Point of contact: 3236 Scott Boulevard Santa Clara, CA 95054

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